

| | | | |
|-----------------------------------|---------------------------------------|-------------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 09/987,477 | Applicant(s)/Patent Under Reexamination OHTAKE ET AL. | |
| | Examiner A. Sefer | Art Unit 2826 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|-----------------|----------------|
| * | A | US-6,630,974 | 10-2003 | Galabova et al. | 349/119 |
| * | B | US-2003/0147030 | 08-2003 | Sone, Takehiko | 349/113 |
| | C | US- | | | |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| * | N | JP 2000-284127 | 10-2000 | Japan | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.